## METAL OXIDE SEMICONDUCTOR FIELD EFFECT TRANSISTOR

	(MOS	FET)
1.	Input impedance of MOSSFET is  a. less than of FET but more than BJT  b. more than that of FET and BJT  c. more than that of FET but less than BJT  d. less than that of FET and BJT	
2.	MOSFET uses the electric field of  a. gate capacitance to control the channel  b. barrier potential of p-n junction to cont  c. both a and b  d. none of these	
3.	In MOSFET devices the N-channel type is be a. it has better noise immunity b. it is faster	etter the P-channel type in the following respects c. it is TTL compatible d. it has better drive capability  [GATE-1988]

- 4. In a MOSFET, the polarity of the inversion layer is the same as that of the
  - a. charge on the gate electrode
  - b. minority carriers in the drain
  - c. majority carries in the substrate
  - d. majority carries in the source

[GATE-1989]

5.	IGF	ET I	is a	3

a. Square-law device

c. 3/2 power-low device

b. Half-power device

d. Linear device

- 6. A depletion MOSFET differs from a JFET in the sense that it has no
  - a. channel

c. P-N junction

b. gate

d. Substrate

7.	The extremely high input impedance of a MOSFE	T is prim	arily due to the
	a. absence of its channel		
	b. negative gate-source voltage		
	c. depletion of current carriers		
	d. extremely small leakage current of its gate co	apacitor	
_			
8.	<b>'</b>		
	a. Depletion-mode only		
	<ul><li>b. Enhancement-mode only</li><li>c. Depletion-mode or enhancement-mode</li></ul>		
	d. Low-impedance		
	u. Low-impedance		
9.	CMOS stands for		
	a. Common MOS	c.	p-channel and n-channel devices
	b. Active-load switching	d.	complementary MOS
10	. A D-MOSFET is considered to be a		
	a. Normally off device	c.	
	b. Normally on device	d.	High-power switch
11	. CMOS devices use		
	a. Bipolar transistors	c.	Class A operation
	b. Complementary E-MOSFETs	d.	DMOS devices
	,		
12	. Most small-signal E-MOSFETs are found in		
	a. Heavy-current applications	C.	Disk drives
	b. Discrete circuits	d.	Integrated circuit
12	. The main advantage of CMOS is its		
13	a. High power rating	C.	Switching capability
	b. Small-signal operation	d.	Low power consumption
		٠.	- Ferrer commence.
14	. The main factor which makes a MOSFET likely to	breakdo	-
	a. very low gate capacitance	b.	high leakage current

15. In an E onl a. positiv		aram curren	t Starts Offiy	C.		
b. negati				_	greater tha	n V <sub>GS</sub> (th)
16. The transit		e current car	riers throug	h the chanr	nel of a JFET o	decides it's
characteris a. source				C.	GATE	
b. drain				_	source and	drain
					[GAT	E-1994]
7. channel cu		luces on app annel MOSFE			ive voltage to	the GATE of
					[GAT	E-1994]
a. Increa		ET current (I		oy a rise in t	temperature	
b. Increas	se in MOSF se in BJT cu	ET current (I <sub>I</sub> rrent (I <sub>c</sub> ) EET current (	os)	oy a rise in t		T 4000]
a. Increas b. Increas c. Decrea	se in MOSF se in BJT cu ase in MOSI	ET current (I <sub>I</sub> rrent (I <sub>c</sub> ) EET current (	os)	oy a rise in t		E-1990]
a. Increas b. Increas c. Decrea	se in MOSF se in BJT cu ase in MOSI	ET current (I <sub>I</sub> rrent (I <sub>c</sub> ) EET current (	os)			E-1990]
a. Increas b. Increas c. Decrea d. Decrea	se in MOSF se in BJT cu ase in MOSI	ET current (I <sub>I</sub> rrent (I <sub>c</sub> ) EET current (	os) I <sub>DS</sub> )			<b>E-1990]</b> (d)
a. Increase b. Increase c. Decrease d. Decrease	se in MOSF se in BJT cu ase in MOSI ase in BJT cu	ET current (I <sub>I</sub> rrent (I <sub>C</sub> ) EET current ( urrent (I <sub>C</sub> )	os) I <sub>os</sub> ) Answe	ers	[GAT	
a. Increase b. Increase c. Decrease d. Decrease (b)	se in MOSF se in BJT cu ase in MOSI ase in BJT co	ET current (I <sub>I</sub> rrent (I <sub>C</sub> ) EET current ( urrent (I <sub>C</sub> )	Answe	ers (b)	[ <b>GAT</b>	(d)
<ul><li>a. Increase</li><li>b. Increase</li><li>c. Decrease</li></ul>	se in MOSF se in BJT cu ase in MOSI ase in BJT co 2. 6.	ET current (I <sub>I</sub> rrent (I <sub>C</sub> ) EET current ( urrent (I <sub>C</sub> )  (a) (c)	Answe 3.	ers (b) (d)	<b>[GAT</b> 4. 8.	(d) (c)

d. both (a) and (c)

c. high input resistance